Tulane’s Electron Microscopy Laboratory
Coordinated Instrumentation Facility (CIF)

Location: 3001 & 1032 Percival Stern Hall, Tulane University  Contact: Jibao He, Ph.D., jhe1@tulane.edu, (504) 314-2118

Mission: To provide opportunities in the use of high resolution electron microscopy for academic researchers, to provide training for students, and to assist users with structural and elemental analysis of both biological and materials science samples.

New Instrument: FEI TECNAI G² F30 FEG TEM

JEOL JEM-2010 TEM

Accelerating Voltage: 80-200kV
Point Resolution: 0.19 nm
Capabilities: TEM Imaging, HRTEM, Cryo-TEM, Si-Li EDS, SAED

HITACHI S-4800 FEG CRYO-SEM

Accelerating Voltage: 0-30kV
Point Resolution: 1 nm
Capabilities: SEM & BS Imaging, Cryo-SEM, Si-Li EDS

HITACHI S-3400 FEG VPSEM

Accelerating Voltage: 0-30kV
Point Resolution: 4 nm
Capabilities: SEM & BS Imaging, VP-SEM, Si-Li EDS & WDS

• Easy access for researchers at all universities in the New Orleans area.
• Both cryo SEM and cryo TEM to enable state of the art in biological imaging.
• 3D Tomography for shape reconstruction.
• Highly educational experience for students. Extremely valuable skill.
• Well maintained instruments and very reasonable rates.

All instruments acquired with NSF MRI Funding.
We are dedicated to work with you in electron microscopy analysis!